

# **Dual P-Channel 20 V (D-S) MOSFET**

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)	Q <sub>g</sub> (TYP.) (nC)		
	0.450 at V <sub>GS</sub> = -4.5 V	-0.55			
-20	0.500 at V <sub>GS</sub> = -2.5 V	-0.50	1		
	0.600 at V <sub>GS</sub> = -1.8 V	-0.38			

### **FEATURES**

- TrenchFET® power MOSFET
- 100 % R tested
- Fast switching speed



#### **APPLICATIONS**

- Load / power switch for portable devices
- Drivers: relays, solenoids, displays
- Battery operated systems

		SC-75-6		
S <sub>1</sub>	1		6	D <sub>1</sub>
G <sub>1</sub>	2		5	G <sub>2</sub>
D <sub>2</sub>	3		4	S <sub>2</sub>
		Top View		

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>A</sub> = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	LIMIT	UNIT			
Drain-Source Voltage		V <sub>DS</sub>	-20	V		
Gate-Source Voltage		V <sub>GS</sub>	± 8	¬		
Continuous Drain Current /T 150 °C)	T <sub>A</sub> = 25 °C		-0.55 b, c			
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 70 °C	I <sub>D</sub>	-0.45 <sup>b, c</sup>			
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub>	-1.8	Α Α		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	-0.16 <sup>b, c</sup>			
Maximum Rower Dissination	T <sub>A</sub> = 25 °C	0.19 b, c		W		
Maximum Power Dissipation	T <sub>A</sub> = 70 °C	- P <sub>D</sub> -	0.12 <sup>b, c</sup>			
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum Junction-to-Ambient <sup>a, b</sup>	t ≤ 5 s	В	440 530	530	°C/W	
iviaximum sunction-to-ambient 4, 2	Steady State	$R_{thJA}$	540	650		

#### Notes

- a. Maximum under steady state conditions is 650 °C/W.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 5 s.

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PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static					I.		
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0$ , $I_D = -250 \mu A$	-20	_	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$		-	-12	-	mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = -250 μA	-	1.8	-		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = -250 \mu A$	-0.4	-	-1	V	
Cata Cauraa Laakaga	1	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$	-	-	± 30		
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$		-	± 1		
7 0. 11 5 . 5		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0 V	-	-	-1	— μA —	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 85 °C	-	-	-10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} = \ge 5 \text{ V}, V_{GS} = -4.5 \text{ V}$	-1.5	-	-	Α	
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -0.4 A	-	0.450	1 - 1		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -2.5 \text{ V}, I_D = -0.2 \text{ A}$	-	0.500	-	Ω	
		V <sub>GS</sub> = -1.8 V, I <sub>D</sub> = -0.1 A	-	0.600	-	1	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = 0.4 A	-	1	-	S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>		-	45	-		
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	15	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			10	-		
Tabal Oata Observe		$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V}, I_D = -0.4 \text{ A}$	-	1.65	2.50	nC	
Total Gate Charge			-	1	2		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = -0 V, $V_{GS}$ = -2.5 V, $I_D$ = -0.4	-	0.2	-		
Gate-Drain Charge	$Q_{gd}$		-	0.26	-		
Gate Resistance	$R_g$	f = 1 MHz	2.4	12	24	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		-	9	18		
Rise Time	t <sub>r</sub>	$V_{DD}$ = -10 V, $R_L$ = 33.3 $\Omega$	-	10	20		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D\cong$ -0.3 A, $V_{GEN}=$ -4.5 V, $R_g=$ 1 $\Omega$	-	10	20		
Fall Time	t <sub>f</sub>		-	8	16	ne	
Turn-On Delay Time	t <sub>d(on)</sub>		-	1	2	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = -10 V, $R_L$ = 33.3 $\Omega$	-	8	16		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D\cong$ -0.3 A, $V_{GEN}$ = -8 V, $R_g$ = 1 $\Omega$	-	9	18		
Fall Time	t <sub>f</sub>		-	5	10		
<b>Drain-Source Body Diode Characteris</b>	tics						
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>		-	-	-1.5	Α	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = -0.3 A	-	-0.8	-1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	16	24	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L 0.2 A d1/d+ 100 A/	-	8	16	nC	
Reverse Recovery Fall Time	$I_F = -0.3 \text{ A, dl/dt} = 100 \text{ A/}\mu\text{s}$		-	11	-	ns	
Reverse Recovery Rise Time	t <sub>b</sub>	7		5	-		

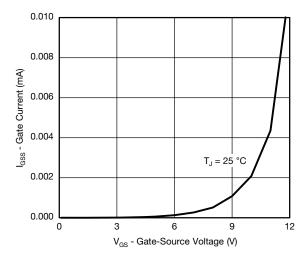
#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

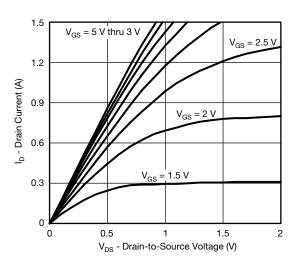
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



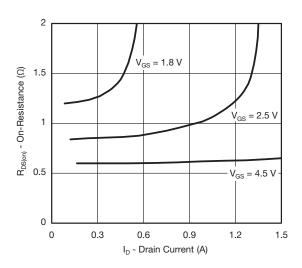
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



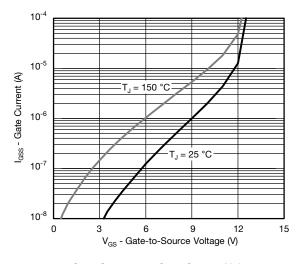
Gate Current vs. Gate-Source Voltage



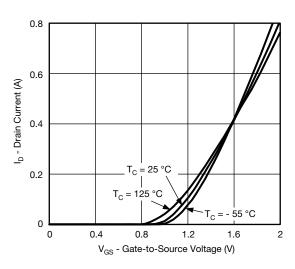
**Output Characteristics** 



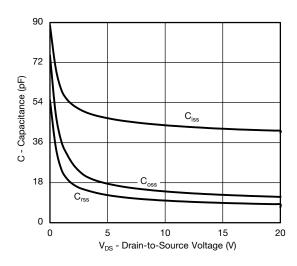
On-Resistance vs. Drain Current



Gate Current vs. Gate-Source Voltage



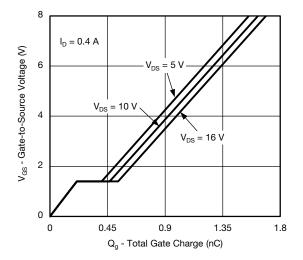
**Transfer Characteristics** 



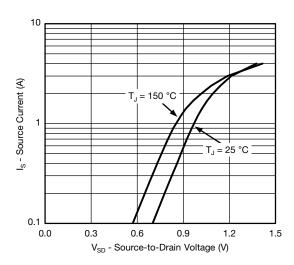
Capacitance



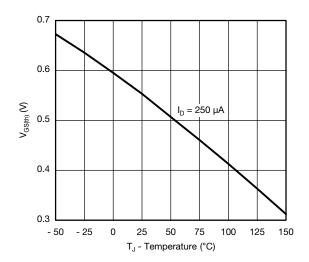
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



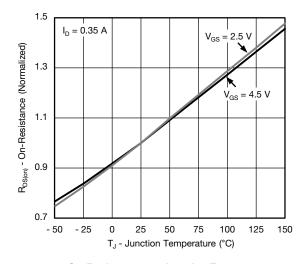
**Gate Charge** 



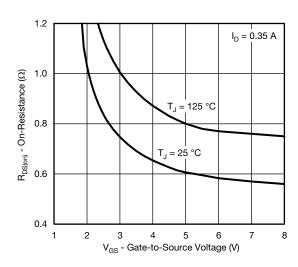
Source-Drain Diode Forward Voltage



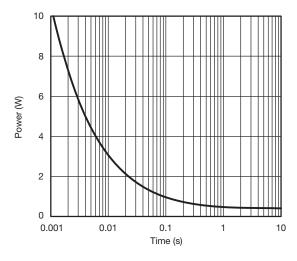
**Threshold Voltage** 



On-Resistance vs. Junction Temperature



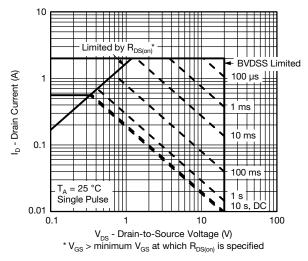
On-Resistance vs. Gate-to-Source Voltage

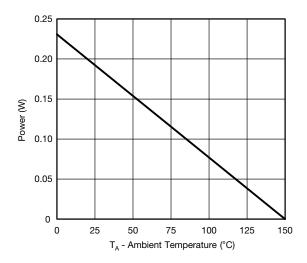


Single Pulse Power, Junction-to-Ambient



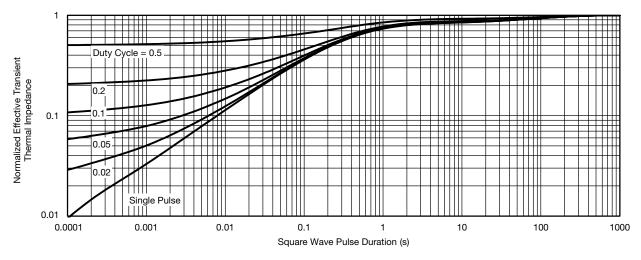
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





Safe Operating Area, Junction-to-Ambient

Power Derating, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Ambient



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